

Notice of References Cited	Application/Control No. 10/561,964		Applicant(s)/Patent Under Reexamination TAKEDA ET AL.	
	Examiner Kianni C. Kaveh		Art Unit 2883	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0113921 A1	08-2002	JIANG et al.	349/96
*	B	US-2003/0076466 A1	04-2003	Ozawa et al.	349/113
*	C	US-2003/0174276 A1	09-2003	Umeya, Masanori	349/194
*	D	US-2004/0145690 A1	07-2004	Kim et al.	349/113
*	E	US-2004/0223102 A1	11-2004	Kwon et al.	349/115
*	F	US-2005/0151896 A1	07-2005	Hara et al.	349/096
*	G	US-2005/0180017 A1	08-2005	Hara et al.	359/619
*	H	US-2005/0249890 A1	11-2005	Murakami et al.	428/001.1
*	I	US-7,075,598 B2	07-2006	Umeya, Masanori	349/98
*	J	US-7,148,513 B2	12-2006	He et al.	257/79
*	K	US-2007/0014127 A1	01-2007	Hara et al.	362/611
*	L	US-7,256,847 B2	08-2007	Kashima, Keiji	349/115
*	M	US-7,317,498 B2	01-2008	Hara et al.	349/62

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.